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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500mc
Number of Cores/Bus Width	4 Core, 32-Bit
Speed	1.3GHz
Co-Processors/DSP	-
RAM Controllers	DDR3, DDR3L
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (5), 10Gbps (1)
SATA	SATA 3Gbps (2)
USB	USB 2.0 + PHY (2)
Voltage - I/O	1.0V, 1.35V, 1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	780-BFBGA
Supplier Device Package	780-FCPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/p2041nxn7nnc

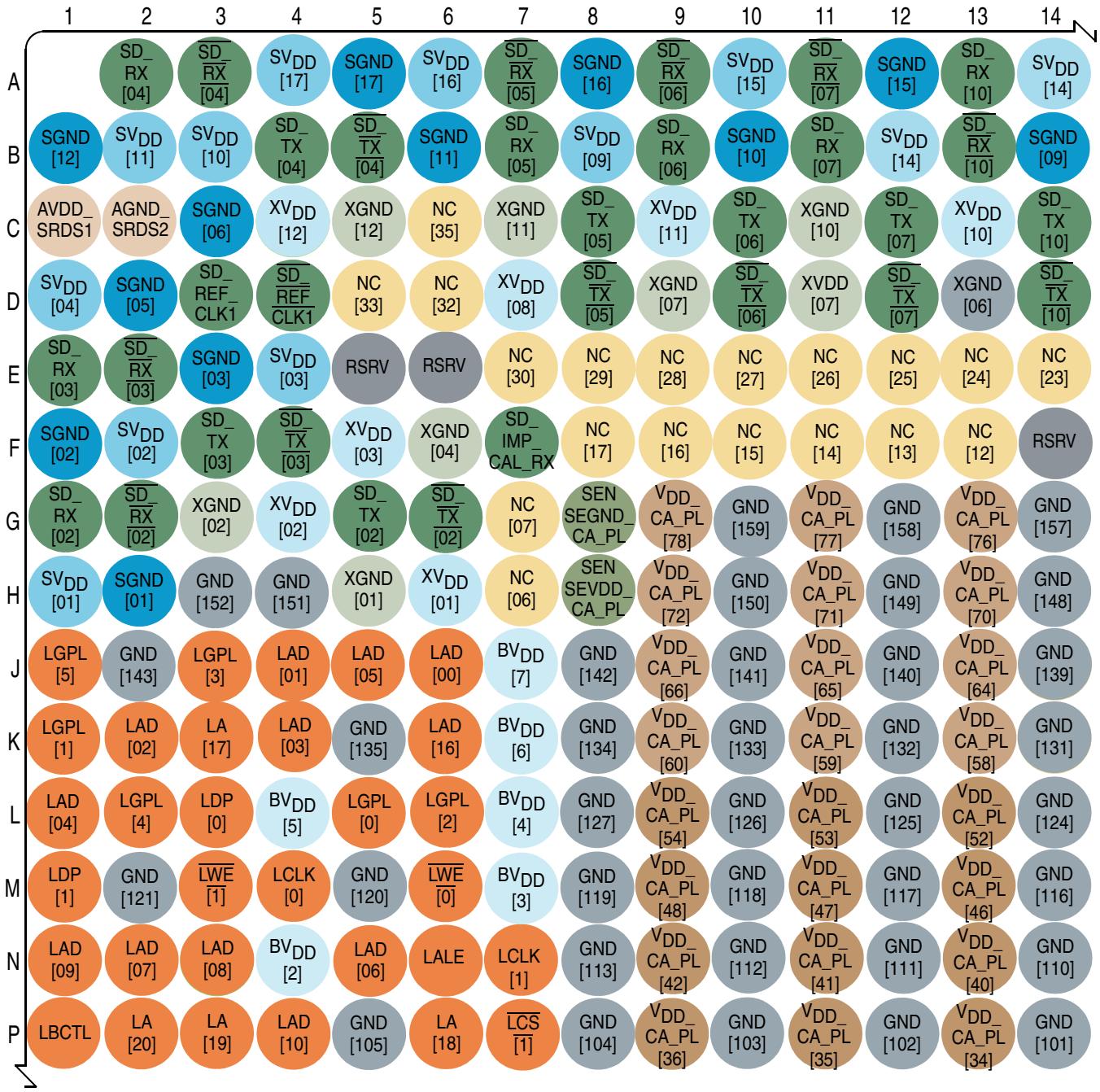


Figure 3. 780 BGA Ball Map Diagram (Detail View A)

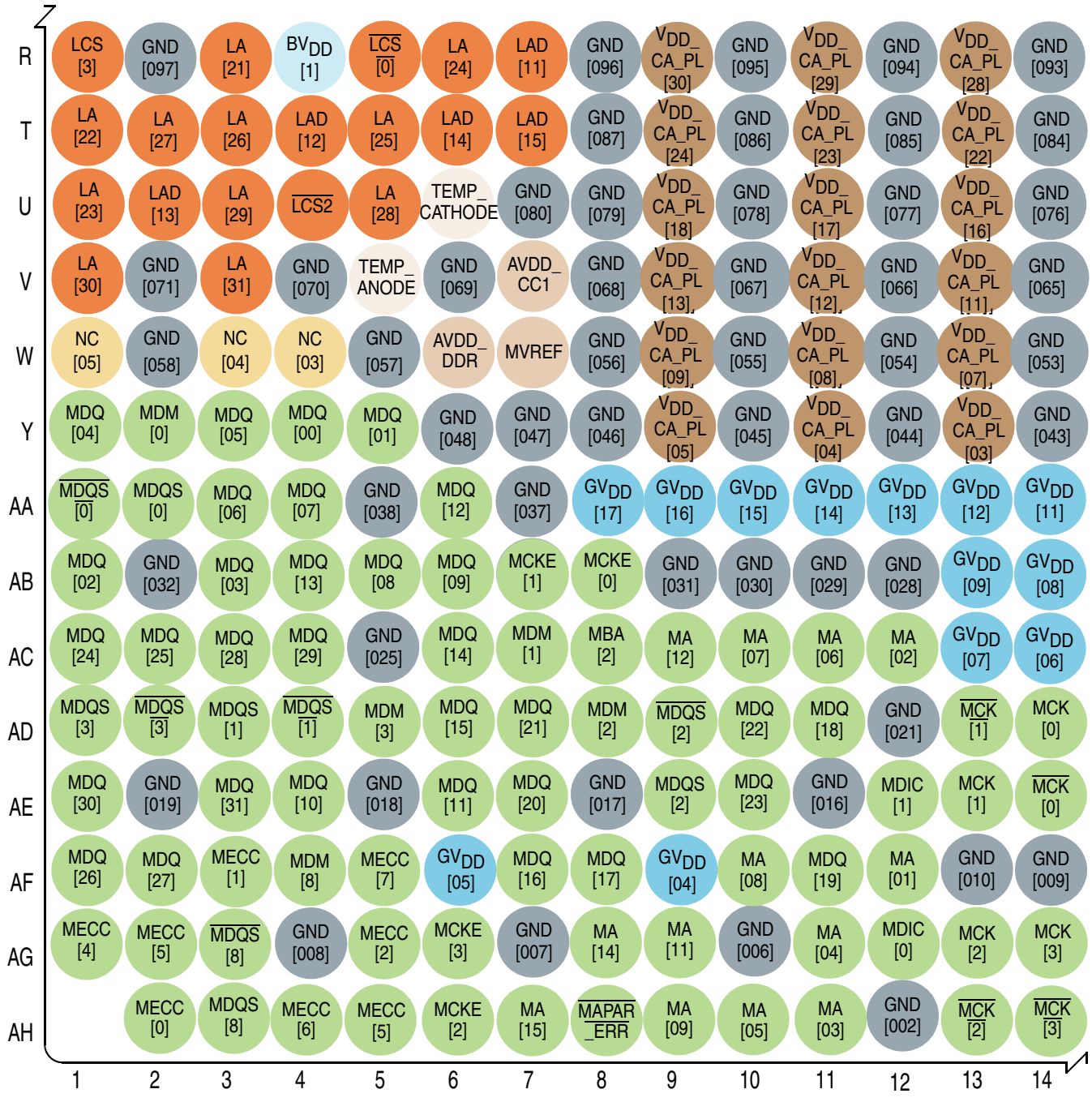


Figure 5. 780 BGA Ball Map Diagram (Detail View C)

1.2 Pinout List

This table provides the pinout listing for the 780 FC-PBGA package by bus. Pins for multiplexed signals appear in the bus group for their default status and have a corresponding note stating that they have multiple functionality depending on the mode in which they are configured.

Table 1. Pin List by Bus

Signal	Signal Description	Package Pin Number	Pin Type	Power Supply	Note
DDR SDRAM Memory Interface					
MDQ00	Data	Y4	I/O	GV_{DD}	—
MDQ01	Data	Y5	I/O	GV_{DD}	—
MDQ02	Data	AB1	I/O	GV_{DD}	—
MDQ03	Data	AB3	I/O	GV_{DD}	—
MDQ04	Data	Y1	I/O	GV_{DD}	—
MDQ05	Data	Y3	I/O	GV_{DD}	—
MDQ06	Data	AA3	I/O	GV_{DD}	—
MDQ07	Data	AA4	I/O	GV_{DD}	—
MDQ08	Data	AB5	I/O	GV_{DD}	—
MDQ09	Data	AB6	I/O	GV_{DD}	—
MDQ10	Data	AE4	I/O	GV_{DD}	—
MDQ11	Data	AE6	I/O	GV_{DD}	—
MDQ12	Data	AA6	I/O	GV_{DD}	—
MDQ13	Data	AB4	I/O	GV_{DD}	—
MDQ14	Data	AC6	I/O	GV_{DD}	—
MDQ15	Data	AD6	I/O	GV_{DD}	—
MDQ16	Data	AF7	I/O	GV_{DD}	—
MDQ17	Data	AF8	I/O	GV_{DD}	—
MDQ18	Data	AD11	I/O	GV_{DD}	—
MDQ19	Data	AF11	I/O	GV_{DD}	—
MDQ20	Data	AE7	I/O	GV_{DD}	—
MDQ21	Data	AD7	I/O	GV_{DD}	—
MDQ22	Data	AD10	I/O	GV_{DD}	—
MDQ23	Data	AE10	I/O	GV_{DD}	—
MDQ24	Data	AC1	I/O	GV_{DD}	—
MDQ25	Data	AC2	I/O	GV_{DD}	—
MDQ26	Data	AF1	I/O	GV_{DD}	—
MDQ27	Data	AF2	I/O	GV_{DD}	—
MDQ28	Data	AC3	I/O	GV_{DD}	—

Table 1. Pin List by Bus (continued)

Signal	Signal Description	Package Pin Number	Pin Type	Power Supply	Note
IRQ05/GPIO23/DMA2_DDONE0	External Interrupts	AA22	I	OV_{DD}	24
IRQ06/GPIO24/USB1_DRVVBUS	External Interrupts	Y26	I	OV_{DD}	24
IRQ07/GPIO25/USB1_PWRFAULT	External Interrupts	AA23	I	OV_{DD}	24
IRQ08/GPIO26/USB2_DRVVBUS	External Interrupts	AC22	I	OV_{DD}	24
IRQ09/GPIO27/USB2_PWRFAULT	External Interrupts	AC27	I	OV_{DD}	24
IRQ10/GPIO28/EVT7	External Interrupts	AB24	I	OV_{DD}	24
IRQ11/GPIO29/EVT8	External Interrupts	AC24	I	OV_{DD}	24
IRQ_OUT/EVT9	Interrupt Output	Y24	O	OV_{DD}	1, 2, 24
Trust					
TMP_DETECT	Tamper Detect	T24	I	OV_{DD}	25
LP_TMP_DETECT	Low Power Tamper Detect	L21	I	V_{DD_LP}	25
eSDHC					
SDHC_CMD	Command/Response	N22	I/O	CV_{DD}	—
SDHC_DAT0	Data	N23	I/O	CV_{DD}	—
SDHC_DAT1	Data	N26	I/O	CV_{DD}	—
SDHC_DAT2	Data	N27	I/O	CV_{DD}	—
SDHC_DAT3	Data	N28	I/O	CV_{DD}	—
SDHC_DAT4/SPI_CS0/GPIO00	Data	H26	I/O	CV_{DD}	24, 28
SDHC_DAT5/SPI_CS1/GPIO01	Data	H23	I/O	CV_{DD}	24, 28
SDHC_DAT6/SPI_CS2/GPIO02	Data	H27	I/O	CV_{DD}	24, 28
SDHC_DAT7/SPI_CS3/GPIO03	Data	H24	I/O	CV_{DD}	24, 28
SDHC_CLK	Host to Card Clock	N24	O	OV_{DD}	—
SDHC_CD/IIC3_SCL/GPIO16/ M1DVAL/LB_DVAL/DMA1_DACK0	Card Detection	AB23	I/O	OV_{DD}	24, 28
SDHC_WP/IIC3_SDA/GPIO17/ M1SRCID0/LB_SRCID0/DMA1_DDONE0	Card Write Protection	AB26	I	OV_{DD}	24, 28
eSPI					
SPI_MOSI	Master Out Slave In	H28	I/O	CV_{DD}	—
SPI_MISO	Master In Slave Out	G23	I	CV_{DD}	—
SPI_CLK	eSPI Clock	H22	O	CV_{DD}	—
SPI_CS0/SDHC_DAT4/GPIO00	eSPI Chip Select	H26	O	CV_{DD}	24
SPI_CS1/SDHC_DAT5/GPIO01	eSPI Chip Select	H23	O	CV_{DD}	24
SPI_CS2/SDHC_DAT6/GPIO02	eSPI Chip Select	H27	O	CV_{DD}	24
SPI_CS3/SDHC_DAT7/GPIO03	eSPI Chip Select	H24	O	CV_{DD}	24

Table 1. Pin List by Bus (continued)

Signal	Signal Description	Package Pin Number	Pin Type	Power Supply	Note
GND132	Ground	K12	—	—	—
GND131	Ground	K14	—	—	—
GND130	Ground	K16	—	—	—
GND129	Ground	K18	—	—	—
GND128	Ground	K21	—	—	—
GND127	Ground	L8	—	—	—
GND126	Ground	L10	—	—	—
GND125	Ground	L12	—	—	—
GND124	Ground	L14	—	—	—
GND123	Ground	L16	—	—	—
GND122	Ground	L18	—	—	—
GND121	Ground	M2	—	—	—
GND120	Ground	M5	—	—	—
GND119	Ground	M8	—	—	—
GND118	Ground	M10	—	—	—
GND117	Ground	M12	—	—	—
GND116	Ground	M14	—	—	—
GND115	Ground	M16	—	—	—
GND114	Ground	M18	—	—	—
GND113	Ground	N8	—	—	—
GND112	Ground	N10	—	—	—
GND111	Ground	N12	—	—	—
GND110	Ground	N14	—	—	—
GND109	Ground	N16	—	—	—
GND108	Ground	N18	—	—	—
GND107	Ground	N21	—	—	—
GND106	Ground	N25	—	—	—
GND105	Ground	P5	—	—	—
GND104	Ground	P8	—	—	—
GND103	Ground	P10	—	—	—
GND102	Ground	P12	—	—	—
GND101	Ground	P14	—	—	—
GND100	Ground	P16	—	—	—
GND099	Ground	P18	—	—	—

Table 1. Pin List by Bus (continued)

Signal	Signal Description	Package Pin Number	Pin Type	Power Supply	Note
GND064	Ground	V16	—	—	—
GND063	Ground	V17	—	—	—
GND062	Ground	V19	—	—	—
GND061	Ground	V21	—	—	—
GND060	Ground	V23	—	—	—
GND059	Ground	V27	—	—	—
GND058	Ground	W2	—	—	—
GND057	Ground	W5	—	—	—
GND056	Ground	W8	—	—	—
GND055	Ground	W10	—	—	—
GND054	Ground	W12	—	—	—
GND053	Ground	W14	—	—	—
GND052	Ground	W17	—	—	—
GND051	Ground	W19	—	—	—
GND050	Ground	W21	—	—	—
GND049	Ground	W23	—	—	—
GND048	Ground	Y6	—	—	—
GND047	Ground	Y7	—	—	—
GND046	Ground	Y8	—	—	—
GND045	Ground	Y10	—	—	—
GND044	Ground	Y12	—	—	—
GND043	Ground	Y14	—	—	—
GND042	Ground	Y16	—	—	—
GND041	Ground	Y17	—	—	—
GND040	Ground	Y19	—	—	—
GND039	Ground	Y22	—	—	—
GND038	Ground	AA5	—	—	—
GND037	Ground	AA7	—	—	—
GND036	Ground	AA17	—	—	—
GND035	Ground	AA19	—	—	—
GND034	Ground	AA24	—	—	—
GND033	Ground	AA27	—	—	—
GND032	Ground	AB2	—	—	—
GND031	Ground	AB9	—	—	—

Table 1. Pin List by Bus (continued)

Signal	Signal Description	Package Pin Number	Pin Type	Power Supply	Note
GND030	Ground	AB10	—	—	—
GND029	Ground	AB11	—	—	—
GND028	Ground	AB12	—	—	—
GND027	Ground	AB15	—	—	—
GND026	Ground	AB22	—	—	—
GND025	Ground	AC5	—	—	—
GND024	Ground	AC17	—	—	—
GND023	Ground	AC20	—	—	—
GND022	Ground	AC26	—	—	—
GND021	Ground	AD12	—	—	—
GND020	Ground	AD15	—	—	—
GND019	Ground	AE2	—	—	—
GND018	Ground	AE5	—	—	—
GND017	Ground	AE8	—	—	—
GND016	Ground	AE11	—	—	—
GND015	Ground	AE15	—	—	—
GND014	Ground	AE18	—	—	—
GND013	Ground	AE21	—	—	—
GND012	Ground	AE24	—	—	—
GND011	Ground	AE27	—	—	—
GND010	Ground	AF13	—	—	—
GND009	Ground	AF14	—	—	—
GND008	Ground	AG4	—	—	—
GND007	Ground	AG7	—	—	—
GND006	Ground	AG10	—	—	—
GND005	Ground	AG19	—	—	—
GND004	Ground	AG22	—	—	—
GND003	Ground	AG25	—	—	—
GND002	Ground	AH12	—	—	—
GND001	Ground	AH15	—	—	—
XGND12	SerDes Transceiver GND	C5	—	—	—
XGND11	SerDes Transceiver GND	C7	—	—	—
XGND10	SerDes Transceiver GND	C11	—	—	—
XGND09	SerDes Transceiver GND	C15	—	—	—

2.1.3 Output Driver Characteristics

This table provides information about the characteristics of the output driver strengths. The values are preliminary estimates.

Table 4. Output Drive Capability

Driver Type	Output Impedance (Ω)	(Nominal) Supply Voltage	Note
Local Bus interface utilities signals	45 45 45	BV_{DD} = 3.3 V BV_{DD} = 2.5 V BV_{DD} = 1.8 V	—
DDR3 signal	20 (full-strength mode) 40 (half-strength mode)	GV_{DD} = 1.5 V	1
DDR3L signal	20 (full-strength mode) 40 (half-strength mode)	GV_{DD} = 1.35 V	1
eTSEC/10/100 signals	45 45	LV_{DD} = 3.3 V LV_{DD} = 2.5 V	—
DUART, system control, JTAG	45	OV_{DD} = 3.3 V	—
I^2C	45	OV_{DD} = 3.3 V	—
eSPI, eSDHC	45 45 45	CV_{DD} = 3.3 V CV_{DD} = 2.5 V CV_{DD} =1.8 V	—

Note:

1. The drive strength of the DDR3 or DDR3L interface in half-strength mode is at T_j = 105 °C and at GV_{DD} (min).

2.2 Power Up Sequencing

The device requires that its power rails be applied in a specific sequence in order to ensure proper device operation. These requirements are as follows for power up:

1. Bring up OV_{DD}, LV_{DD}, BV_{DD}, CV_{DD}, and USB_V_{DD}_3P3. Drive POV_{DD} = GND.
   - — $\overline{\text{PORESET}}$ input must be driven asserted and held during this step.
   - — IO_VSEL inputs must be driven during this step and held stable during normal operation.
   - — USB_V_{DD}_3P3 rise time (10% to 90%) has a minimum of 350 µs.
2. Bring up $V_{DD\_CA\_CB\_PL}$, SV_{DD}, AV_{DD} (cores, platform, SerDes) and USB_V_{DD}_1P0. $V_{DD\_CA\_CB\_PL}$ and USB_V_{DD}_1P0 must be ramped up simultaneously.
3. Bring up GV_{DD} (DDR) and XV_{DD}.
4. Negate $\overline{\text{PORESET}}$ input as long as the required assertion/hold time has been met per Table 17.
5. For secure boot fuse programming: After negation of $\overline{\text{PORESET}}$, drive POV_{DD} = 1.5 V after a required minimum delay per Table 5. After fuse programming is completed, it is required to return POV_{DD} = GND before the system is power cycled ($\overline{\text{PORESET}}$ assertion) or powered down ($V_{DD\_CA\_CB\_PL}$ ramp down) per the required timing specified in Table 5. See Section 5, "Security Fuse Processor," for additional details.

WARNING

Only two secure boot fuse programming events are permitted per lifetime of a device.

No activity other than that required for secure boot fuse programming is permitted while POV_{DD} driven to any voltage above GND, including the reading of the fuse block. The reading of the fuse block may only occur while POV_{DD} = GND.

While VDD is ramping, current may be supplied from VDD through the chip to GVDD. Nevertheless, GVDD from an external supply should follow the sequencing described above.

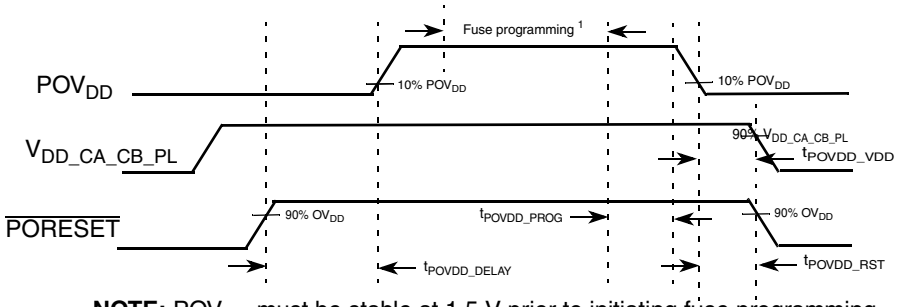
WARNING

Only 100,000 POR cycles are permitted per lifetime of a device.

All supplies must be at their stable values within 75 ms.

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

This figure provides the POV_{DD} timing diagram.



NOTE: POV_{DD} must be stable at 1.5 V prior to initiating fuse programming.

Figure 8. POV_{DD} Timing Diagram

This table provides information on the power-down and power-up sequence parameters for POV_{DD}.

Table 5. POV_{DD} Timing [5]

Driver Type	Min	Max	Unit	Note
t_{POVDD_DELAY}	100	—	SYSCLKs	1
t_{POVDD_PROG}	0	—	µs	2
t_{POVDD_VDD}	0	—	µs	3
t_{POVDD_RST}	0	—	µs	4

Note:

1. Delay required from the negation of $\overline{\text{PORESET}}$ to driving POV_{DD} ramp up. Delay measured from $\overline{\text{PORESET}}$ negation at 90% OV_{DD} to 10% POV_{DD} ramp up.
2. Delay required from fuse programming finished to POV_{DD} ramp down start. Fuse programming must complete while POV_{DD} is stable at 1.5 V. No activity other than that required for secure boot fuse programming is permitted while POV_{DD} driven to any voltage above GND, including the reading of the fuse block. The reading of the fuse block may only occur while POV_{DD} = GND. After fuse programming is completed, it is required to return POV_{DD} = GND.
3. Delay required from POV_{DD} ramp down complete to $V_{DD\_CA\_CB\_PL}$ ramp down start. POV_{DD} must be grounded to minimum 10% POV_{DD} before $V_{DD\_CA\_CB\_PL}$ is at 90% V_{DD}.
4. Delay required from POV_{DD} ramp down complete to $\overline{\text{PORESET}}$ assertion. POV_{DD} must be grounded to minimum 10% POV_{DD} before $\overline{\text{PORESET}}$ assertion reaches 90% OV_{DD}.
5. Only two secure boot fuse programming events are permitted per lifetime of a device.

To guarantee MCKE low during power up, the above sequencing for GV_{DD} is required. If there is no concern about any of the DDR signals being in an indeterminate state during power up, the sequencing for GV_{DD} is not required.

Table 13. SYSCLK AC Timing Specifications

For recommended operating conditions, see Table 3.

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
SYSCLK frequency	f_{SYSCLK}	67	—	133	MHz	1, 2
SYSCLK cycle time	t_{SYSCLK}	7.5	—	15	ns	1, 2
SYSCLK duty cycle	t_{KHK}/t_{SYSCLK}	40	—	60	%	2
SYSCLK slew rate	—	1	—	4	V/ns	3
SYSCLK peak period jitter	—	—	—	±150	ps	—
SYSCLK jitter phase noise at – 56dBc	—	—	—	500	KHz	4
AC Input Swing Limits at 3.3 V OV_{DD}	ΔV_{AC}	1.9	—	—	V	—

Note:

1. **Caution:** The relevant clock ratio settings must be chosen such that the resulting SYSCLK frequency, do not exceed their respective maximum or minimum operating frequencies.
2. Measured at the rising edge and/or the falling edge at $OV_{DD} \div 2$.
3. Slew rate as measured from ± 0.3 $\Delta \mathbf{V_{AC}}$ at center of peak to peak voltage at clock input.
4. Phase noise is calculated as FFT of TIE jitter.

2.6.2 Spread Spectrum Sources

Spread spectrum clock sources are an increasingly popular way to control electromagnetic interference emissions (EMI) by spreading the emitted noise to a wider spectrum and reducing the peak noise magnitude in order to meet industry and government requirements. These clock sources intentionally add long-term jitter to diffuse the EMI spectral content. The jitter specification given in this table considers short-term (cycle-to-cycle) jitter only. The clock generator's cycle-to-cycle output jitter should meet the device input cycle-to-cycle jitter requirement. Frequency modulation and spread are separate concerns; the device is compatible with spread spectrum sources if the recommendations listed in this table are observed.

Table 14. Spread Spectrum Clock Source Recommendations

For recommended operating conditions, see Table 3.

Parameter	Min	Max	Unit	Note
Frequency modulation	—	60	kHz	—
Frequency spread	—	1.0	%	1, 2

Note:

1. SYSCLK frequencies that result from frequency spreading and the resulting core frequency must meet the minimum and maximum specifications given in Table 13.
2. Maximum spread spectrum frequency may not result in exceeding any maximum operating frequency of the device.

CAUTION

The processor's minimum and maximum SYSCLK and core/platform/DDR frequencies must not be exceeded regardless of the type of clock source. Therefore, systems in which the processor is operated at its maximum rated core/platform/DDR frequency should avoid violating the stated limits by using down-spreading only.

This figure shows the DDR3 and DDR3L SDRAM interface output timing for the MCK to MDQS skew measurement (t_{DDKHMH}).

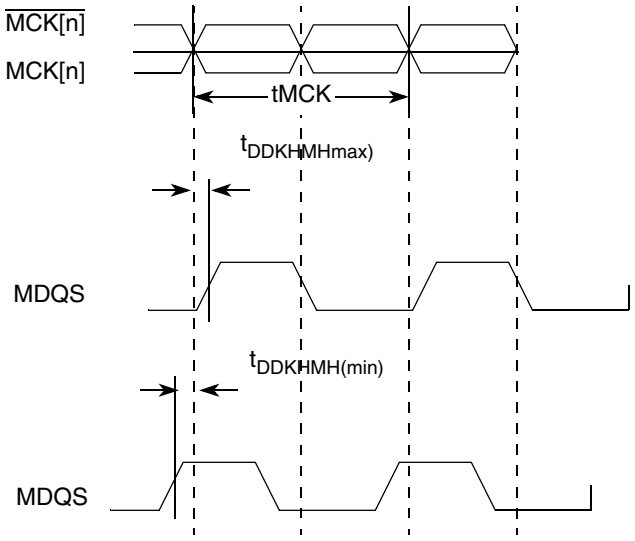


Figure 10. t_{DDKHMH} Timing Diagram

This figure shows the DDR3 and DDR3L SDRAM output timing diagram.

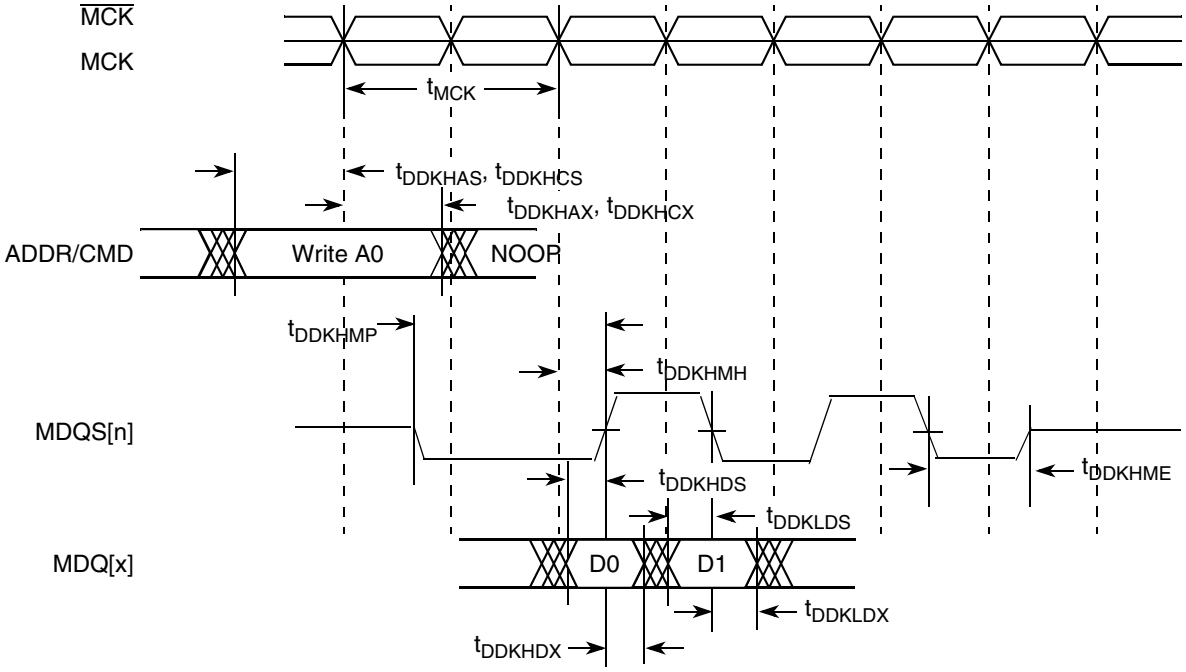


Figure 11. DDR3 and DDR3L Output Timing Diagram

2.12.2.2 RGMII AC Timing Specifications

This table shows the RGMII AC timing specifications.

Table 37. RGMII AC Timing Specifications

For recommended operating conditions, see Table 3.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Note
Data to clock output skew (at transmitter)	t_{SKRGT_TX}	–500	0	500	ps	5
Data to clock input skew (at receiver)	t_{SKRGT_RX}	1.0	—	2.8	ns	2
Clock period duration	t_{RGT}	7.2	8.0	8.8	ns	3
Duty cycle for 10BASE-T and 100BASE-TX	t_{RGTH}/t_{RGT}	40	50	60	%	3, 4
Duty cycle for Gigabit	t_{RGTH}/t_{RGT}	45	50	55	%	—
Rise time (20%–80%)	t_{RGTR}	—	—	0.75	ns	—
Fall time (20%–80%)	t_{RGTF}	—	—	0.75	ns	—

Note:

1. In general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII timing. Note that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
2. This implies that PC board design requires clocks to be routed such that an additional trace delay of greater than 1.5 ns is added to the associated clock signal. Many PHY vendors already incorporate the necessary delay inside their chip. If so, additional PCB delay is probably not needed.
3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
5. The frequency of RX_CLK should not exceed the frequency of GTX_CLK125 by more than 300ppm.

This figure shows the AC timing diagram of the local bus interface.

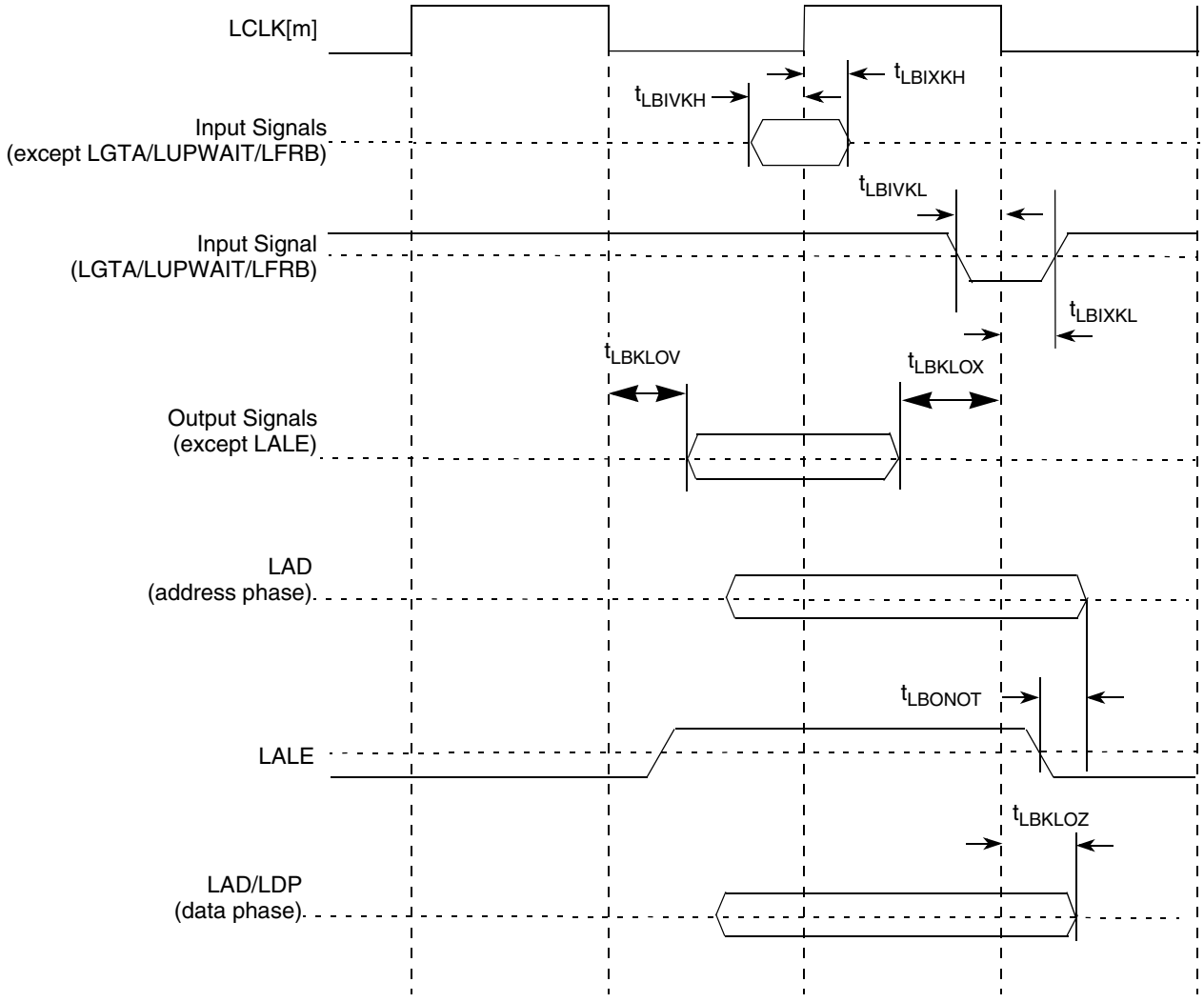


Figure 21. Enhanced Local Bus Signals

Figure 22 applies to all three controllers that eLBC supports: GPCM, UPM, and FCM.

For input signals, the AC timing data is used directly for all three controllers.

For output signals, each type of controller provides its own unique method to control the signal timing. The final signal delay value for output signals is the programmed delay plus the AC timing delay. For example, for GPCM, LCS can be programmed to delay by t_{acs} (0, ¼, ½, 1, 1 + ¼, 1 + ½, 2, 3 cycles), so the final delay is $t_{acs} + t_{LBKLOV}$.

2.17.2 JTAG AC Timing Specifications

This table provides the JTAG AC timing specifications as defined in Figure 25 through Figure 28.

Table 55. JTAG AC Timing Specifications

For recommended operating conditions, see Table 3.

Parameter	Symbol[1]	Min	Max	Unit	Note
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at OVDD/2 V	t_{JTKHKL}	15	—	ns	—
JTAG external clock rise and fall times	t_{JTGR}/t_{JTGF}	0	2	ns	—
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	2
Input setup times Boundary-scan USB only Boundary (except USB) TDI, TMS	t_{JTDVKH}	 14 4 4	—	ns	—
Input hold times	t_{JTDXKH}	10	—	ns	—
Output valid times Boundary-scan data TDO	t_{JTKLDV}	—	 15 10	ns	3
Output hold times	t_{JTKLDX}	0	—	ns	3

Note:

1. The symbols used for timing specifications follow the pattern $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{JTDVKH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDXKH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) reaching the invalid state (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. $\overline{\text{TRST}}$ is an asynchronous level sensitive signal. The setup time is for test purposes only.
3. All outputs are measured from the midpoint voltage of the falling edge of t_{TCLK} to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load. Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.

This figure provides the AC test load for TDO and the boundary-scan outputs of the device.

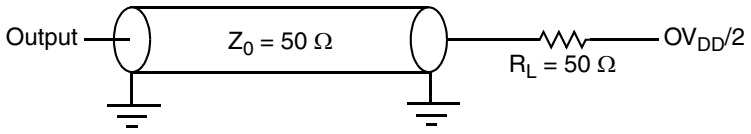


Figure 25. AC Test Load for the JTAG Interface

This table defines the receiver DC specifications for Serial RapidIO operating at XV_{DD} = 1.5 V or 1.8 V.

Table 71. Serial RapidIO Receiver DC Timing Specifications—2.5 GBaud, 3.125 GBaud, 5 GBaud

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Note
Differential input voltage	V_{IN}	200	—	1600	mV p-p	1

Note:
1. Measured at the receiver.

2.20.5.5 AC Requirements for Serial RapidIO

This section explains the AC requirements for the Serial RapidIO interface.

2.20.5.5.1 AC Requirements for Serial RapidIO Transmitter

This table defines the transmitter AC specifications for the Serial RapidIO interface. The AC timing specifications do not include RefClk jitter.

Table 72. Serial RapidIO Transmitter AC Timing Specifications

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typical	Max	Unit
Deterministic jitter	J_D	—	—	0.17	UI p-p
Total jitter	J_T	—	—	0.35	UI p-p
Unit interval: 2.5 GBaud	UI	400 – 100ppm	400	400 + 100ppm	ps
Unit interval: 3.125 GBaud	UI	320 – 100ppm	320	320 + 100ppm	ps

This table defines the receiver AC specifications for Serial RapidIO. The AC timing specifications do not include RefClk jitter.

Table 73. Serial RapidIO Receiver AC Timing Specifications

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typical	Max	Unit	Note
Deterministic jitter tolerance	J_D	0.37	—	—	UI p-p	1
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	—	UI p-p	1
Total jitter tolerance[2]	J_T	0.65	—	—	UI p-p	1
Bit error rate	BER	—	—	10^{-12}	—	—
Unit interval: 2.5 GBaud	UI	400 – 100ppm	400	400 + 100ppm	ps	—
Unit interval: 3.125 GBaud	UI	320 – 100ppm	320	320 + 100ppm	ps	—

Note:
1. Measured at receiver
2. Total jitter is composed of three components: deterministic jitter, random jitter, and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 42. The sinusoidal jitter component is included to ensure margin for low-frequency jitter, wander, noise, crosstalk, and other variable system effects.

Table 83. Gen1i/1.5 G Transmitter (Tx) AC Specifications (continued)

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Note

Note:
1. Measured at Tx output pins peak to peak phase variation, random data pattern

This table provides the differential transmitter output AC characteristics for the SATA interface at Gen2i or 3.0 Gbits/s transmission. The AC timing specifications do not include RefClk jitter.

Table 84. Gen 2i/3 G Transmitter (Tx) AC Specifications

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Note
Channel speed	t_{CH_SPEED}	—	3.0	—	Gbps	—
Unit Interval	T_{UI}	333.2167	333.3333	335.1167	ps	—
Total jitter $f_{C3dB} = f_{BAUD} \div 10$	$U_{SATA\_TXTJfB/10}$	—	—	0.3	UI p-p	1
Total jitter $f_{C3dB} = f_{BAUD} \div 500$	$U_{SATA\_TXTJfB/500}$	—	—	0.37	UI p-p	1
Total jitter $f_{C3dB} = f_{BAUD} \div 1667$	$U_{SATA\_TXTJfB/1667}$	—	—	0.55	UI p-p	1
Deterministic jitter, $f_{C3dB} = f_{BAUD} \div 10$	$U_{SATA\_TXDJfB/10}$	—	—	0.17	UI p-p	1
Deterministic jitter, $f_{C3dB} = f_{BAUD} \div 500$	$U_{SATA\_TXDJfB/500}$	—	—	0.19	UI p-p	1
Deterministic jitter, $f_{C3dB} = f_{BAUD} \div 1667$	$U_{SATA\_TXDJfB/1667}$	—	—	0.35	UI p-p	1

Note:
1. Measured at Tx output pins peak-to-peak phase variation, random data pattern

2.20.7.4 AC Differential Receiver Input Characteristics

This table provides the Gen1i or 1.5 Gbits/s differential receiver input AC characteristics for the SATA interface. The AC timing specifications do not include RefClk jitter.

Table 85. Gen 1i/1.5G Receiver (Rx) AC Specifications

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typical	Max	Unit	Note
Unit Interval	T_{UI}	666.4333	666.6667	670.2333	ps	—
Total jitter data-data 5 UI	$U_{SATA\_TXTJ5UI}$	—	—	0.43	UI p-p	1
Total jitter, data-data 250 UI	$U_{SATA\_TXTJ250UI}$	—	—	0.60	UI p-p	1
Deterministic jitter, data-data 5 UI	$U_{SATA\_TXDJ5UI}$	—	—	0.25	UI p-p	1
Deterministic jitter, data-data 250 UI	$U_{SATA\_TXDJ250UI}$	—	—	0.35	UI p-p	1

Note:
1. Measured at receiver.

Table 89. SGMII DC Receiver Electrical Characteristics (XV_{DD} = 1.5 V or 1.8 V) (continued)

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Note

Note:
1. Input must be externally AC coupled.
2. $V_{RX\_DIFFp\text{-}p}$ is also referred to as peak-to-peak input differential voltage.
3. The concept of this parameter is equivalent to the electrical idle detect threshold parameter in PCI Express. Refer to Section 2.20.4.4, "PCI Express DC Physical Layer Receiver Specifications," and Section 2.20.4.5.2, "PCI Express AC Physical Layer Receiver Specifications," for further explanation.
4. The REIDL_CTL shown in the table refers to the chip's SerDes control register B(1–3)GCR(lane)1[REIDL_CTL] bit field.

This table defines the SGMII 2.5x receiver DC electrical characteristics for 3.125 GBaud.

Table 90. SGMII 2.5x Receiver DC Timing Specifications (XV_{DD} = 1.5 V or 1.8 V)

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typical	Max	Unit	Note
Differential input voltage	V_{IN}	200	900	1600	mV p-p	1

Note:
1. Measured at the receiver.

2.20.8.2 SGMII AC Timing Specifications

This section discusses the AC timing specifications for the SGMII interface.

2.20.8.2.1 SGMII Transmit AC Timing Specifications

This table provides the SGMII transmit AC timing specifications. A source synchronous clock is not supported. The AC timing specifications do not include RefClk jitter.

Table 91. SGMII Transmit AC Timing Specifications

For recommended operating conditions, see Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Note
Deterministic jitter	JD	—	—	0.17	UI p-p	—
Total jitter	JT	—	—	0.35	UI p-p	1
Unit interval: 1.25 GBaud	UI	800 – 100 ppm	800	800 + 100 ppm	ps	—
Unit interval: 3.125 GBaud	UI	320 – 100 ppm	320	320 + 100 ppm	ps	—
AC coupling capacitor	C_{TX}	10		200	nF	2

Note:
1. See Figure 42 for single frequency sinusoidal jitter measurements.
2. The external AC coupling capacitor is required. It is recommended that it be placed near the device transmitter outputs.

2.20.8.2.2 SGMII AC Measurement Details

Transmitter and receiver AC characteristics are measured at the transmitter outputs (SD_TX*n* and $\overline{\text{SD\_TX}n}$) or at the receiver inputs (SD_RX*n* and $\overline{\text{SD\_RX}n}$) respectively, as depicted in this figure.

"e500mc Core Cluster to SYSCLK PLL Ratio." The frequency for each core complex 0–3 is selected using the configuration bits as described in Table 96.

- The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 3.1.2, "Platform to SYSCLK PLL Ratio."
- The DDR block PLL generates the DDR clock from the externally supplied SYSCLK input (asynchronous mode) or from the platform clock (synchronous mode). The frequency ratio is selected using the Memory Controller Complex PLL multiplier/ratio configuration bits as described in Section 3.1.5, "DDR Controller PLL Ratios."
- Each of the three SerDes blocks has a PLL which generate a core clock from their respective externally supplied SD_REF_CLK*n*/$\overline{\text{SD\_REF\_CLK}n}$ inputs. The frequency ratio is selected using the SerDes PLL ratio configuration bits as described in Section 3.1.6, "Frequency Options."

3.1.1 Clock Ranges

This table provides the clocking specifications for the processor core, platform, memory, and local bus.

Table 93. Processor Clocking Specifications

Parameter	Maximum Processor Core Frequency								Unit	Note
	667 MHz		800 MHz		1000 MHz		1200 MHz			
	Min	Max	Min	Max	Min	Max	Min	Max		
e500mc core PLL frequency	667	667	667	800	667	1000	667	1200	MHz	1,4
e500mc core frequency	333	667	333	800	333	1000	333	1200	MHz	4, 8
Platform clock frequency	400	533	400	533	400	533	400	600	MHz	1
Memory bus clock frequency	400	533	400	533	400	533	400	600	MHz	1,2,5,6
Local bus clock frequency	—	67	—	67	—	67	—	75	MHz	3
PME	—	267	—	267	—	267	—	300	MHz	7
FMan	—	467	—	467	—	467	—	500	MHz	—

Note:

1. **Caution:** The platform clock to SYSCLK ratio and e500-mc core to SYSCLK ratio settings must be chosen such that the resulting SYSCLK frequency, e500mc (core) frequency, and platform clock frequency do not exceed their respective maximum or minimum operating frequencies.
2. The memory bus clock speed is half the DDR3/DDR3L data rate. DDR3 memory bus clock frequency is limited to min = 400 MHz.
3. The local bus clock speed on LCLK[0:1] is determined by the platform clock divided by the local bus ratio programmed in LCRR[CLKDIV]. See the chip reference manual for more information.
4. The e500mc core can run at e500mc core complex PLL/1 or PLL/2. With a minimum core complex PLL frequency of 667 MHz, this results in a minimum allowable e500mc core frequency of 333 MHz for PLL/2.
5. In synchronous mode, the memory bus clock speed is half the platform clock frequency. In other words, the DDR data rate is the same as the platform frequency. If the desired DDR data rate is higher than the platform frequency, asynchronous mode must be used.
6. In asynchronous mode, the memory bus clock speed is dictated by its own PLL.
7. The PME runs synchronously to the platform clock, running at a frequency of platform clock/2.
8. Core frequency must be at least as fast as the platform frequency (Rev 1.1 silicon).

3.6.2 Aurora Configuration Signals

Correct operation of the Aurora interface requires configuration of a group of system control pins as demonstrated in Figure 56 and Figure 57. Care must be taken to ensure that these pins are maintained at a valid negated state under normal operating conditions as most have asynchronous behavior and spurious assertion will give unpredictable results.

Freescale recommends that the Aurora 22 pin duplex connector be designed into the system as shown in Figure 58 or the 70 pin duplex connector be designed into the system as shown in Figure 59.

If the Aurora interface is not used, Freescale recommends the legacy COP header be designed into the system as described in Section 3.6.1.1, "Termination of Unused Signals."

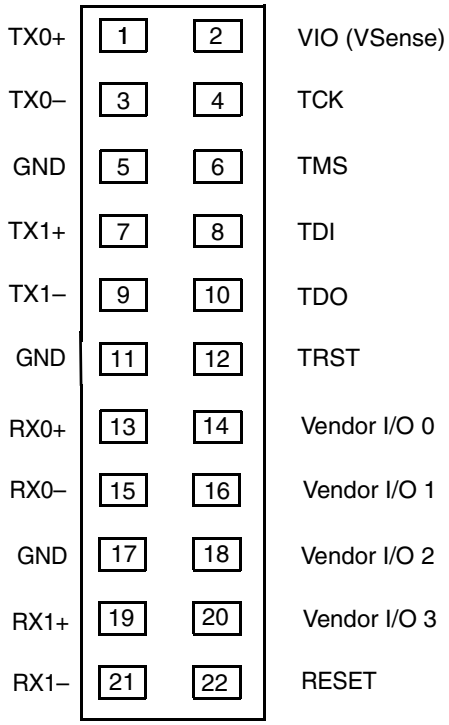
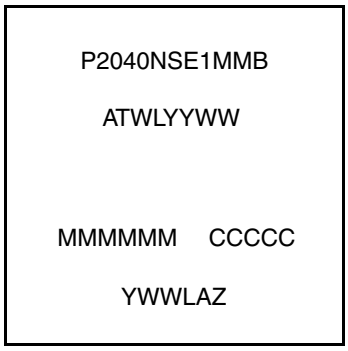


Figure 56. Aurora 22 Pin Connector Duplex Pinout

6.2.1 Part Marking

Parts are marked as in the example shown in this figure.



FC-PBGA

Notes:

P2040NSE1MMB is the orderable part number. See Table 107 for details.

ATWLYYWW is the test traceability code.
MMMMMM is the mask number.

CCCCC is the country code.

YWWLAZ is the assembly traceability code.

Figure 64. Part Marking for FC-PBGA Device

7 Revision History

This table provides a revision history for this document.

Table 108. Revision History

Rev. Number	Date	Description
2	02/2013	• In Table 7, “P2040 I/O Power Supply Estimated Values,” updated the USB power supply with USB_Vdd_3P3 and updated the typical value with “0.003” in the Others (Reset, System Clock, JTAG & Misc.) row. • In Table 8, “Device AVDD Power Dissipation,” removed V_{DD_LP} from table. • Added Table 10, “VDD_LP Power Dissipation.” • In Table 53, “MPIC Input AC Timing Specifications,” added Trust inputs AC timing and footnote 2. • In Table 93, “Processor Clocking Specifications,” updated footnote 8 with Rev 1.1 silicon. • In Table 107, “Part Numbering Nomenclature,” added “C” in the Die Revision collumn. • In Section 6.2, “Orderable Part Numbers Addressed by this Document,” added the device part numbers for Rev 2.0 silicon.